Search Notes

-	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/630,948	HANG, WEI ZHAN
	Examiner	Art Unit
	Phi D. A	3637

	SEAR	CHED	
Class	Subclass	Date	Examiner
52	506.08	9/14/2005	PA
	509		
	- 510		
	506.09		
	506.1		
	511		/
	545		V
	506.06		
		٠	

INI	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
			DATE	EXMR
PA				
				*
·				1